

## Publications de Arhab SLIMANE – Liste des publications depuis 2011

### Articles dans des revues à comité de lecture :

S. Arhab and G. Soriano. "Inverse wave scattering of rough surfaces with emitters and receivers in the transition zone" *Progress In Electromagnetics Research M*, Vol. 45, 131–141, (2016).

S. Arhab, H. Ayasso, B. Duchêne and A. Mohammad-Djafari. "Optical imaging in a variational Bayesian framework" *Journal of Physics : Conference Series*, IOP Publishing, (2014), 542, pp.012008

S. Arhab, G. Soriano, Y. Ruan, G. Maire, A. Talneau, D. Sentenac, P. C. Chaumet, K. Belkebir, H. Giovannini. "Nanometric resolution with far-field optical profilometry" *Phys. Rev. Lett.* 111, 053902 (2013).

S. Arhab, H. Giovannini, K. Belkebir and G. Soriano. "Full polarization optical profilometry" *JOSA A*, Vol. 29, Issue 8, pp. 1508-1515 (2012).

S. Arhab, G. Soriano, K. Belkebir, A. Sentenac, and H. Giovannini. "Full wave optical profilometry" *JOSA A*, Vol. 28, Issue 4, pp. 576-580 (2011).

### Actes de colloque avec comité de lecture :

S. Arhab, M. Joelson and G. Soriano. "Reconstruction of surface profiles by iterative Newton-Kantorovitch's method" 4th Workshop on Remote Sensing and Modelling of Surface Properties (RSMSP). 14-16 March (2016), Maison Jean Kuntz-mann, Saint Martin d'Hères, France.

A. Alwakil, G. Soriano, K. Belkebir, H. Giovannini and S. Arhab. "Direct and iterative inverse wave scattering methods for time-harmonic far-field profilometry" *Antenna Measurements and Applications (CAMA)*, (2014) IEEE.

S. Arhab, G. Soriano, G. Maire, P.C. Chaumet, K. Belkebir, Y. Ruan and H. Giovannini. "High resolution optical profilometry with tomographic diffractive microscopy" *Focus on Microscopy* (2013) (Maastricht, Pays-Bas).

G. Soriano, S. Arhab, K. Belkebir. "Reconstruction of a rough surface profile with an iterative method based on a rigorous direct wave scattering model" *General Assembly and Scientific Symposium*, (2011) XXXth URSI.

S. Arhab, G. Soriano, K. Belkebir, A. Sentenac, and H. Giovannini. "High Resolution Optical Profilometry Using Diffractive Tomographic Microscopy" *PIERS* (2011) in Marrakesh.